THE ELECTRONICS INDUSTRY'S MOST DRAMATIC INTEGRATED TESTING STORY BEGINS WITH A LINE LIKE THIS:

Design Automation Products
HILO® Universal Logic Simulation System
HICHIP™ Universal Hardware Modeling System
HIPOST™-ST HILO to GenRad VLSI Tester Interface
VLSI Test Products
GR125 VLSI Test System
GR160 VLSI Test System
GR180 Complex VLSI/VHSIC Test System
Incoming Inspection Products
1657 & 1658 Digibridge® RLC Testers
1687-B 1MHz LC Digibridge
1689M Precision RLC Digibridge
1731M Linear IC Test System
1732M Digital IC Test System
1734M Memory Test System
SCAN™ Semiconductor Component Analysis Network
1752 Elevated Temperature Handler
2295 Programming Station
Board Test Products
2272 High Pin Count In-circuit/Functional Tester
2276 XP High Performance In-circuit/Functional Tester
2276E Expandable In-circuit/Functional Tester
2276 ICA In-circuit/Functional Analyzer
2275 Low Cost In-circuit/Functional Tester
2293 & 2294 Programming Stations
BusBust®, Scratchprobing and AC Quadrature Bridge
Diagnostic Tools
Automatic Test Generation (ATG)
It takes experience with a full line of test products to have a full understanding of integrated testing.

That’s why our integrated testers of today are designed to fit into the completely integrated testing environment of tomorrow.

And that’s no story.